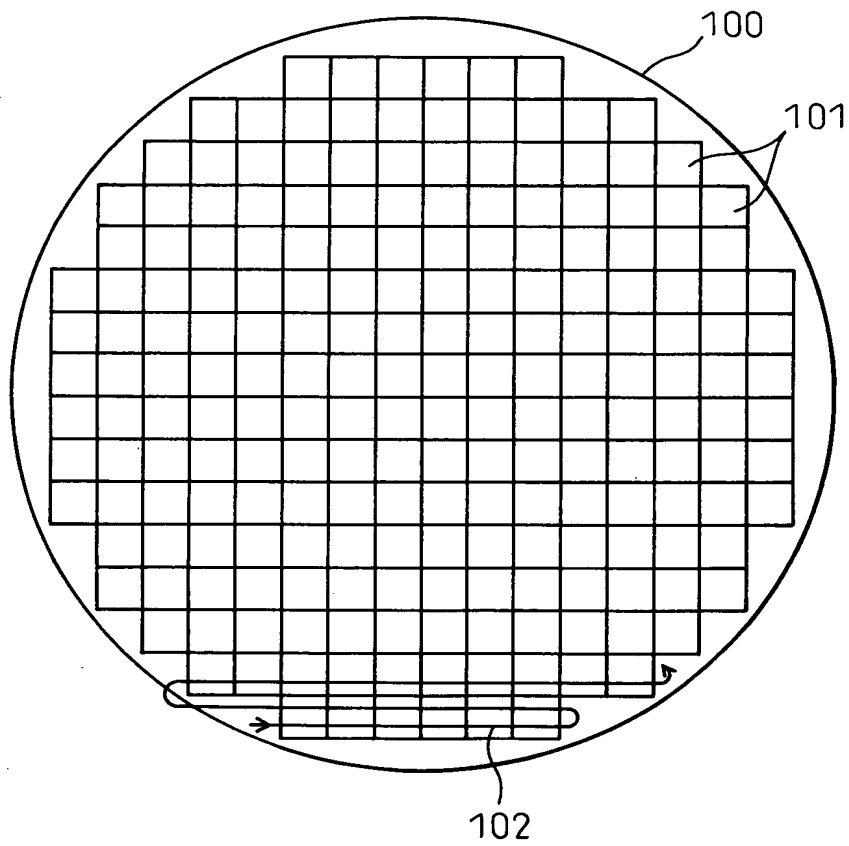


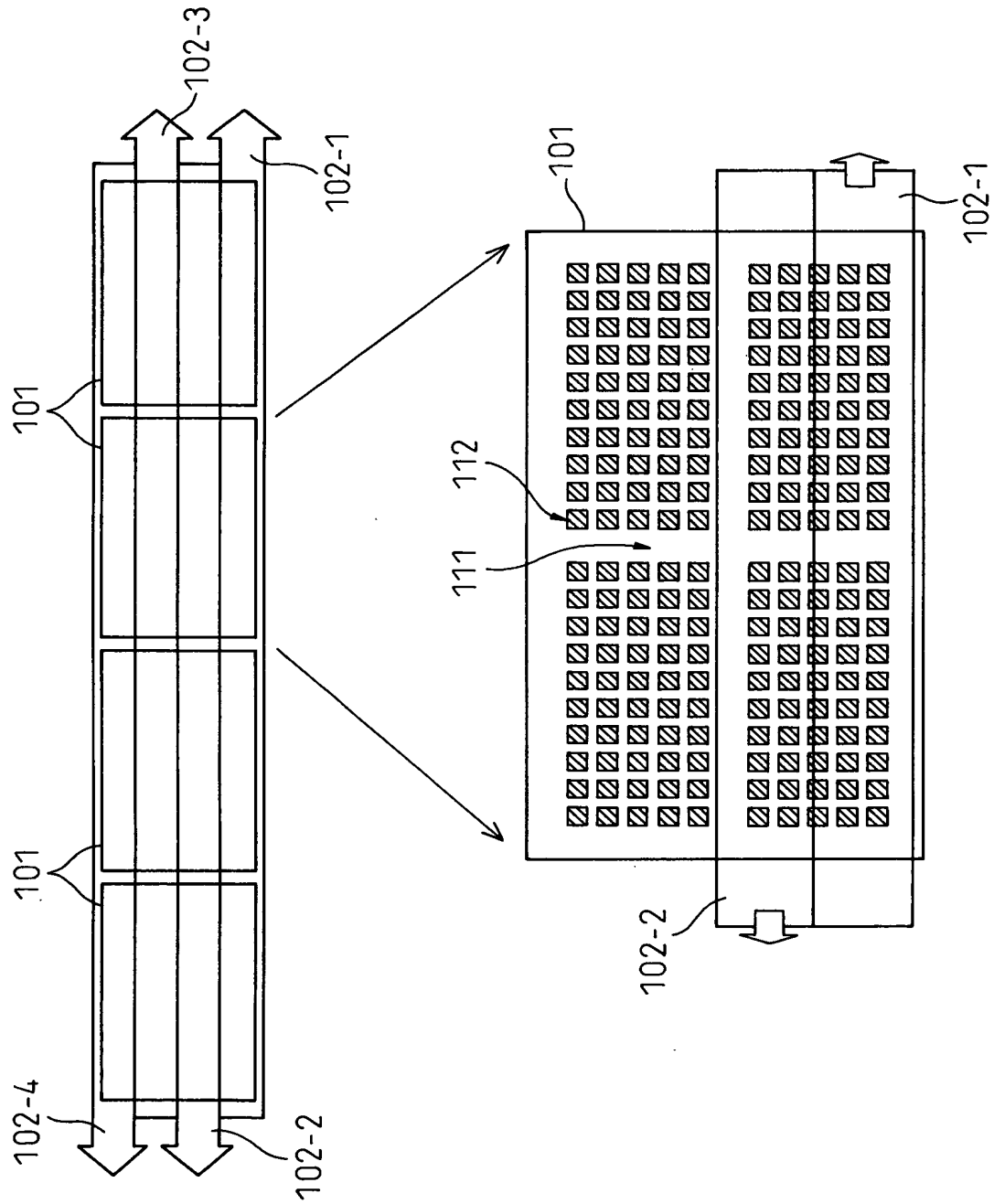
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FIG. 1



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FIG. 2



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FIG.3A

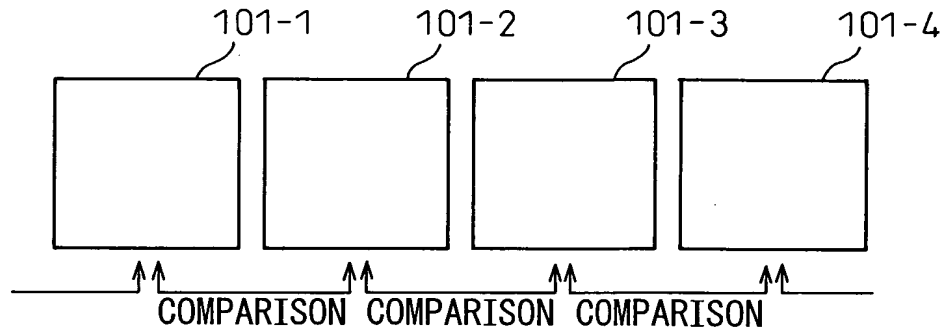


FIG.3B

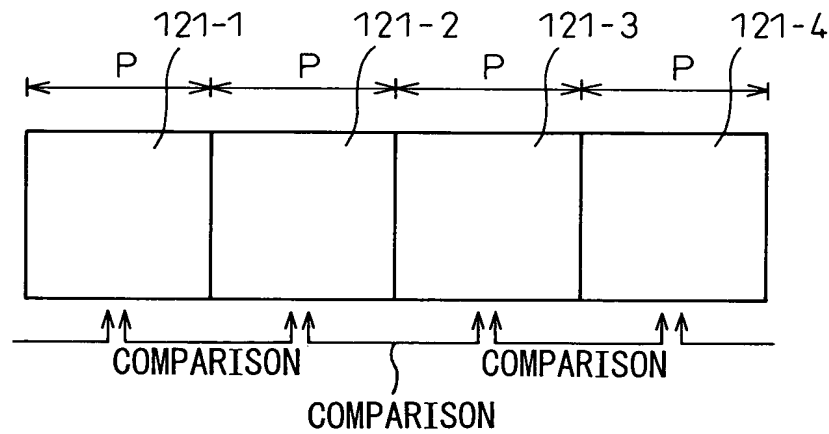


FIG.3C

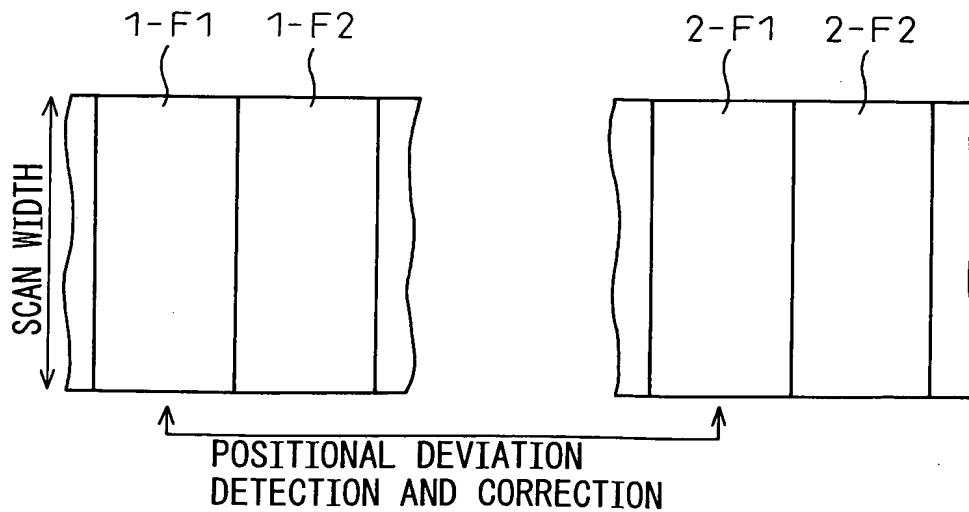
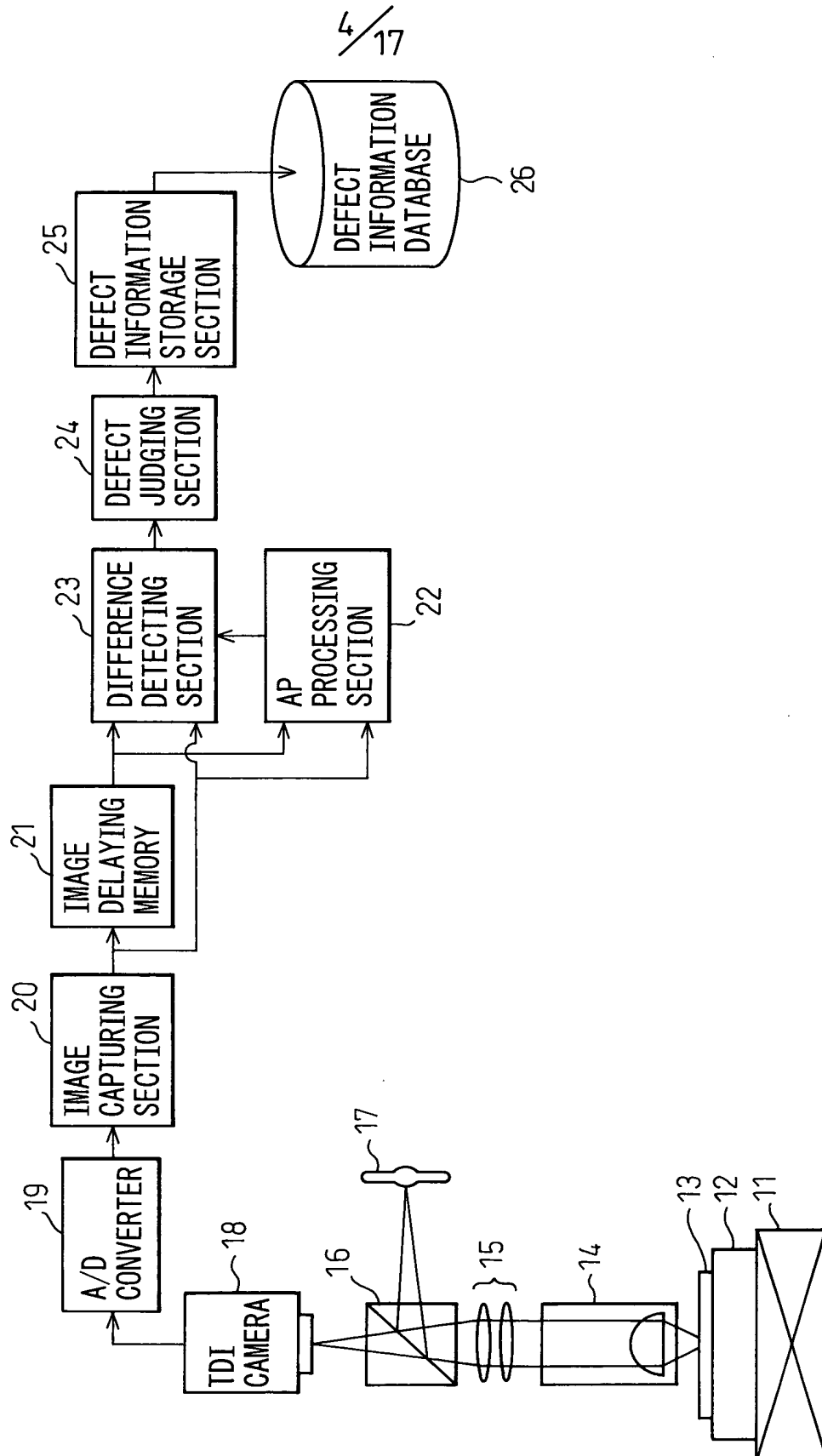
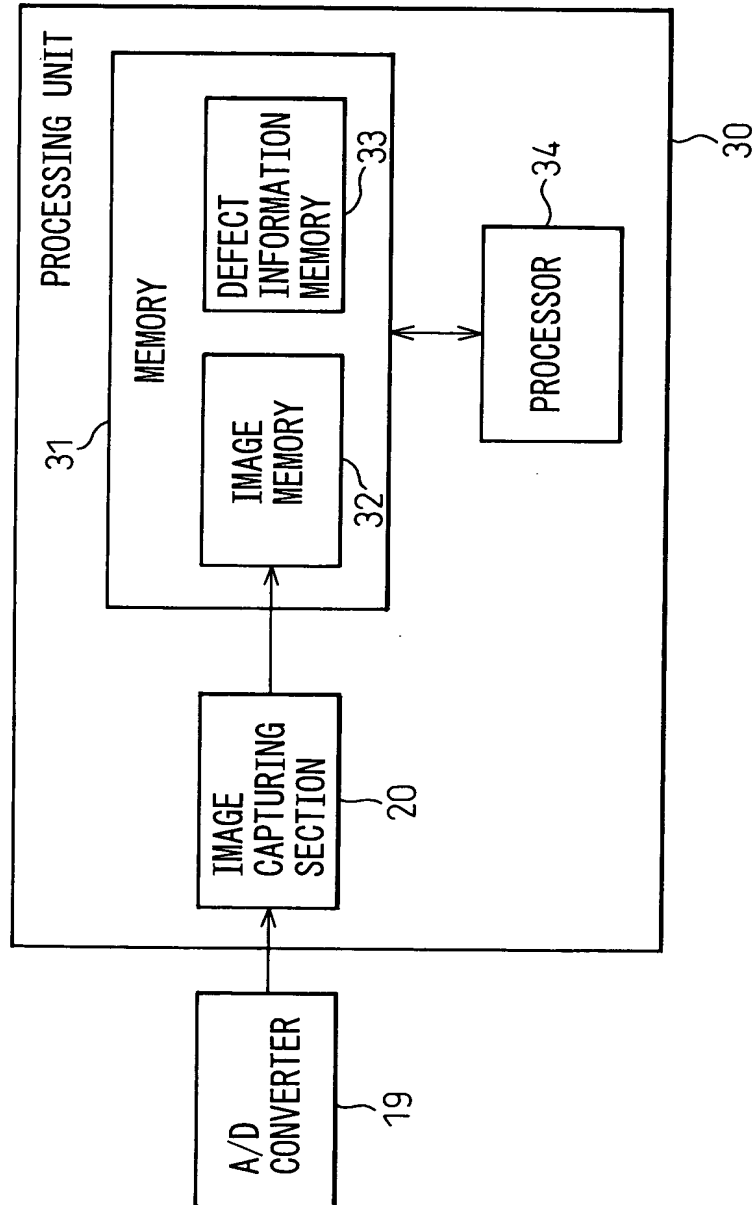


FIG. 4



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FIG. 5



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FIG.6A

DIE COMPARISON INSPECTION

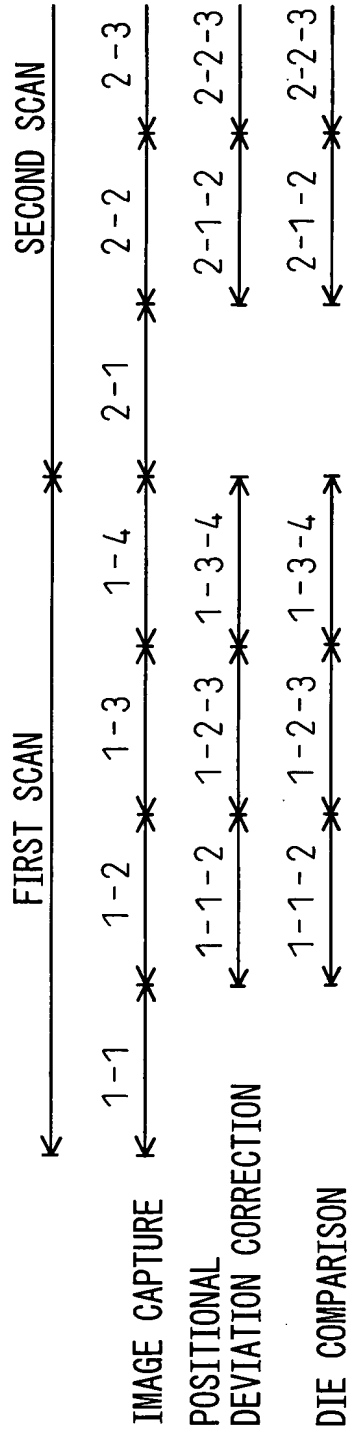
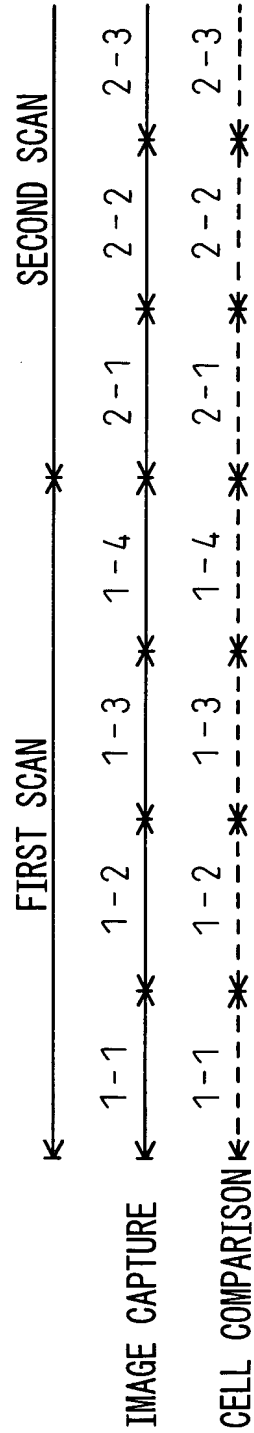


FIG.6B

CELL COMPARISON INSPECTION



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FIG.7

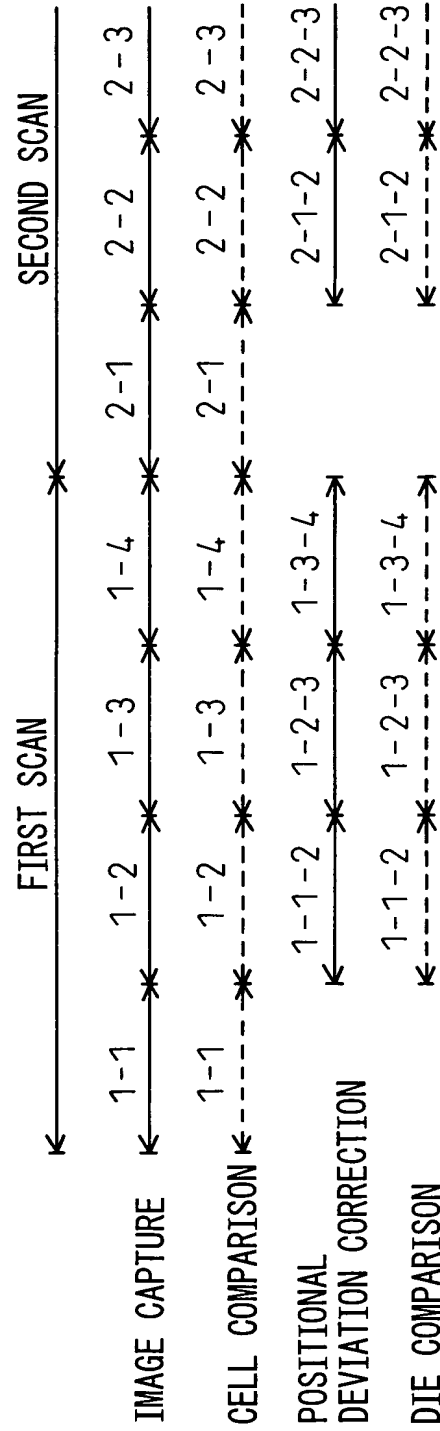
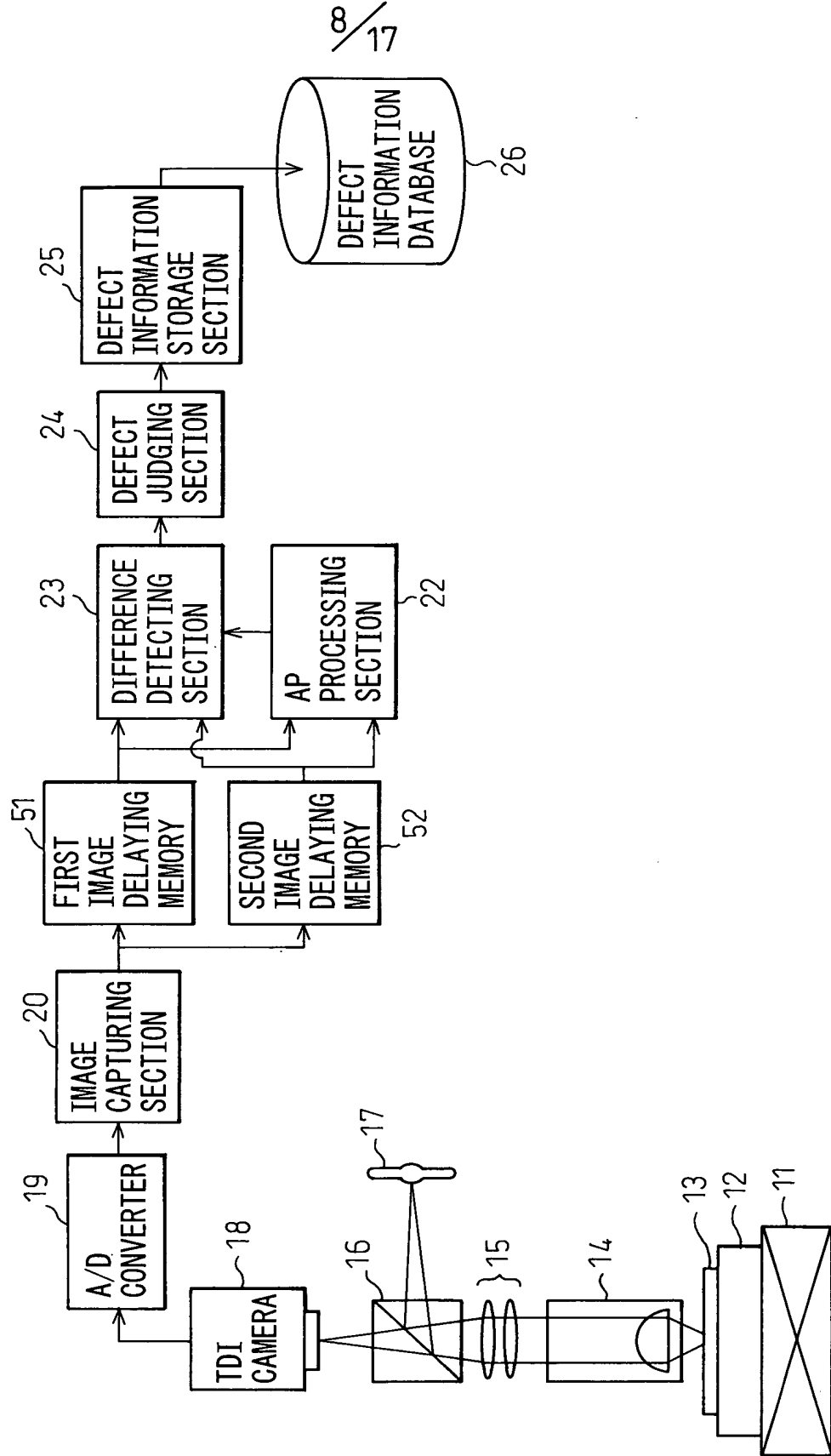
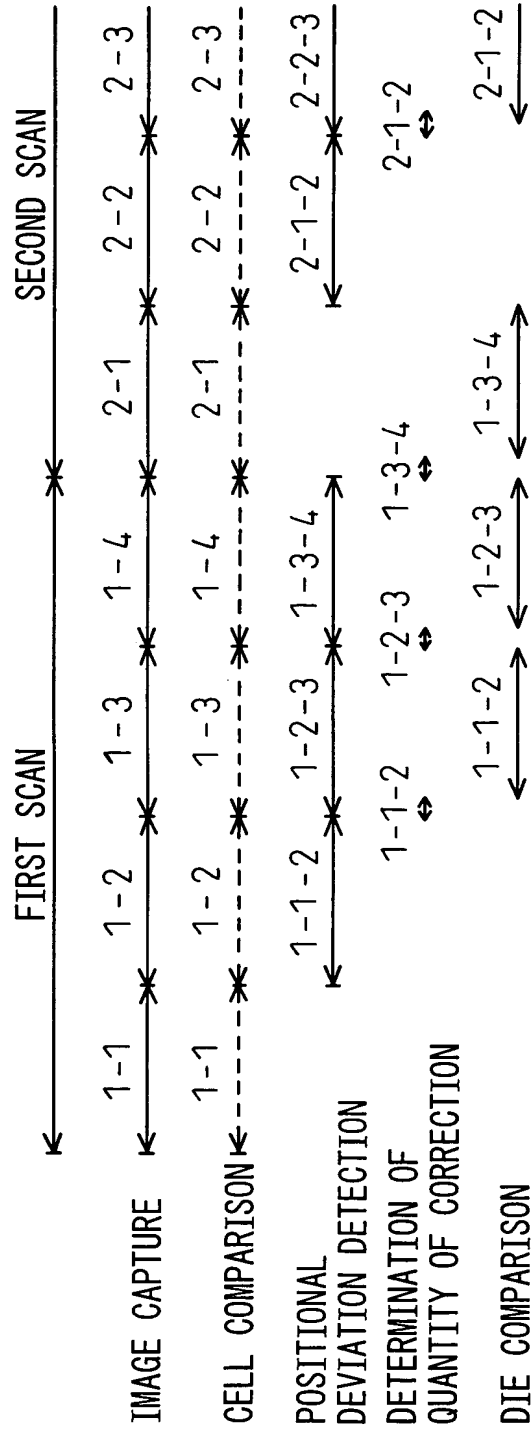


FIG.8



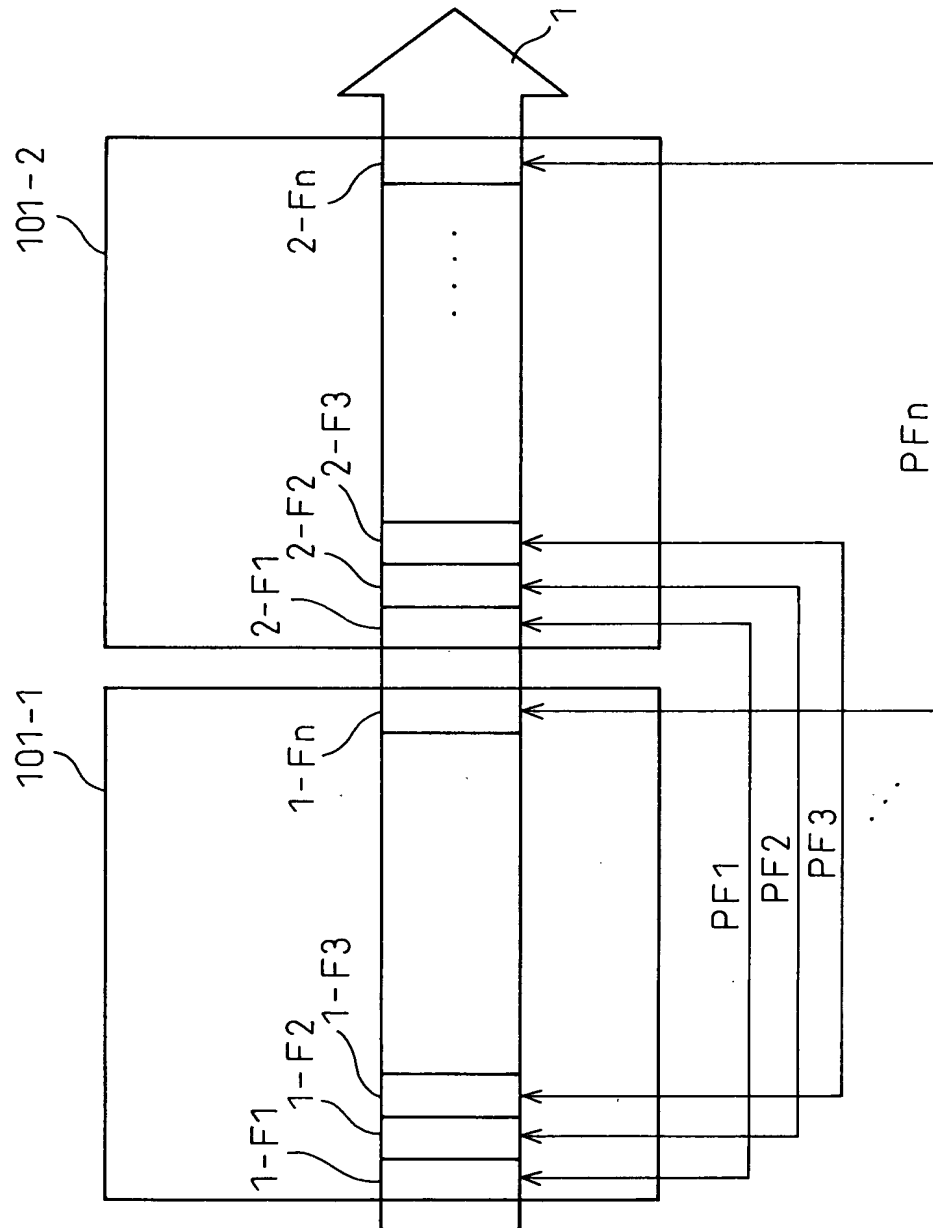
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FIG.9



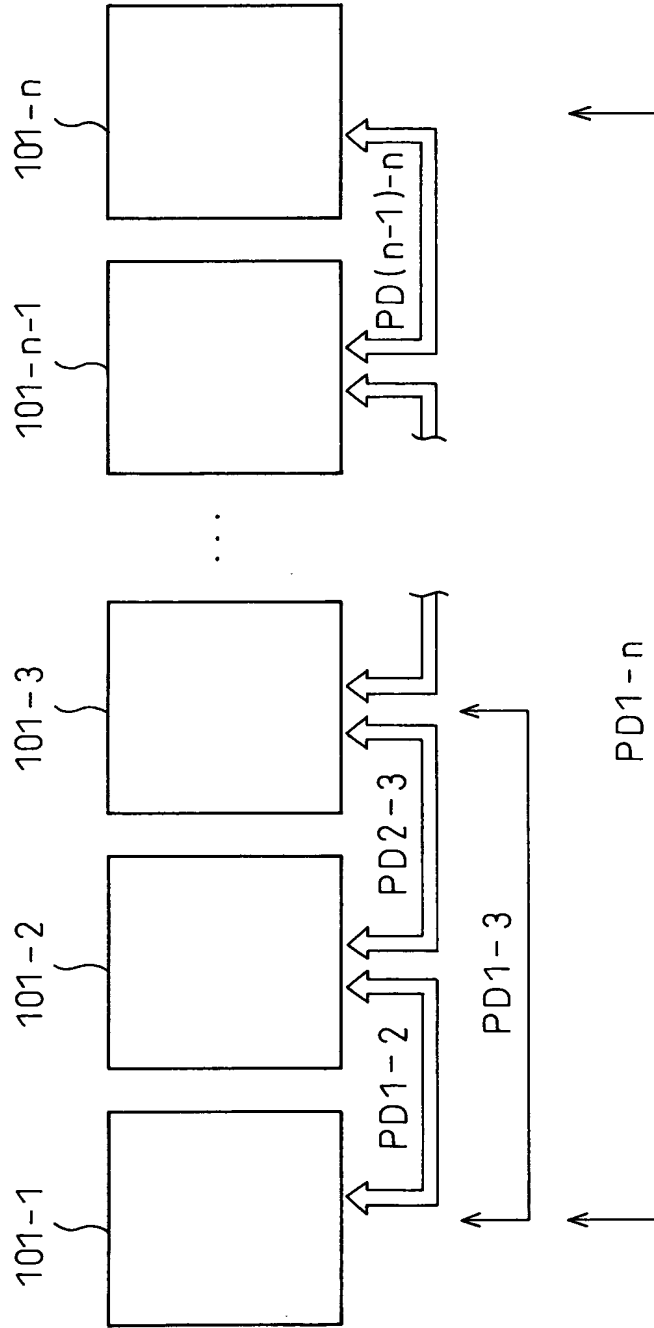
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FIG.10



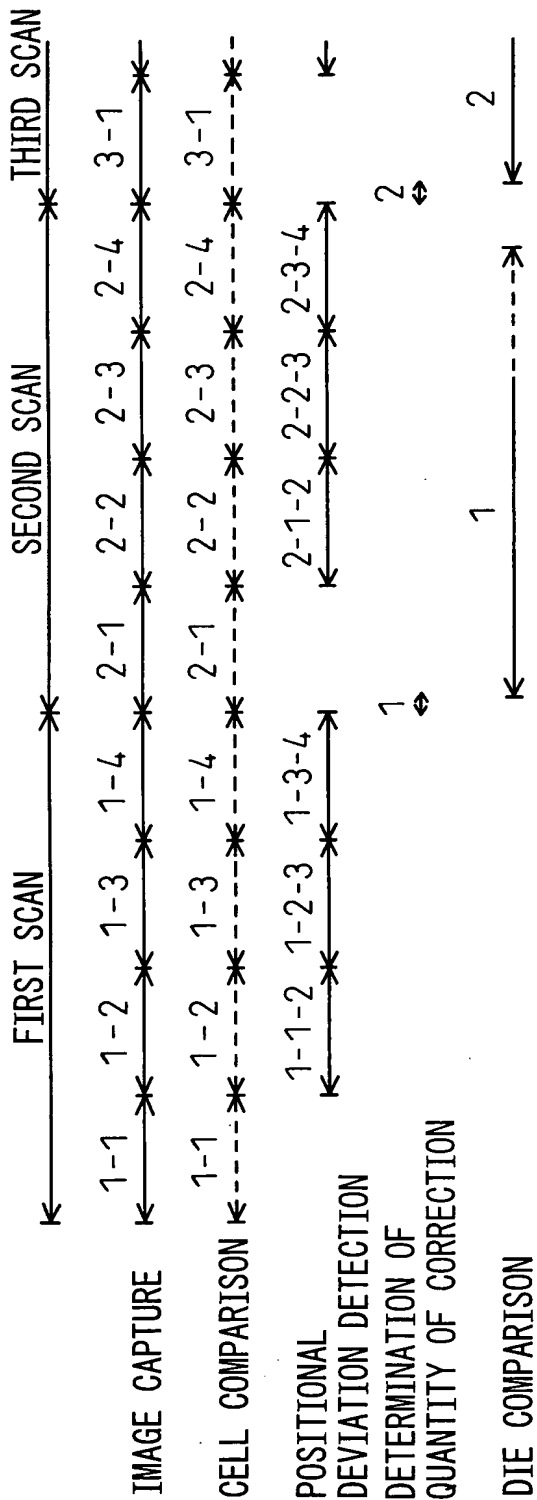
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FIG.11



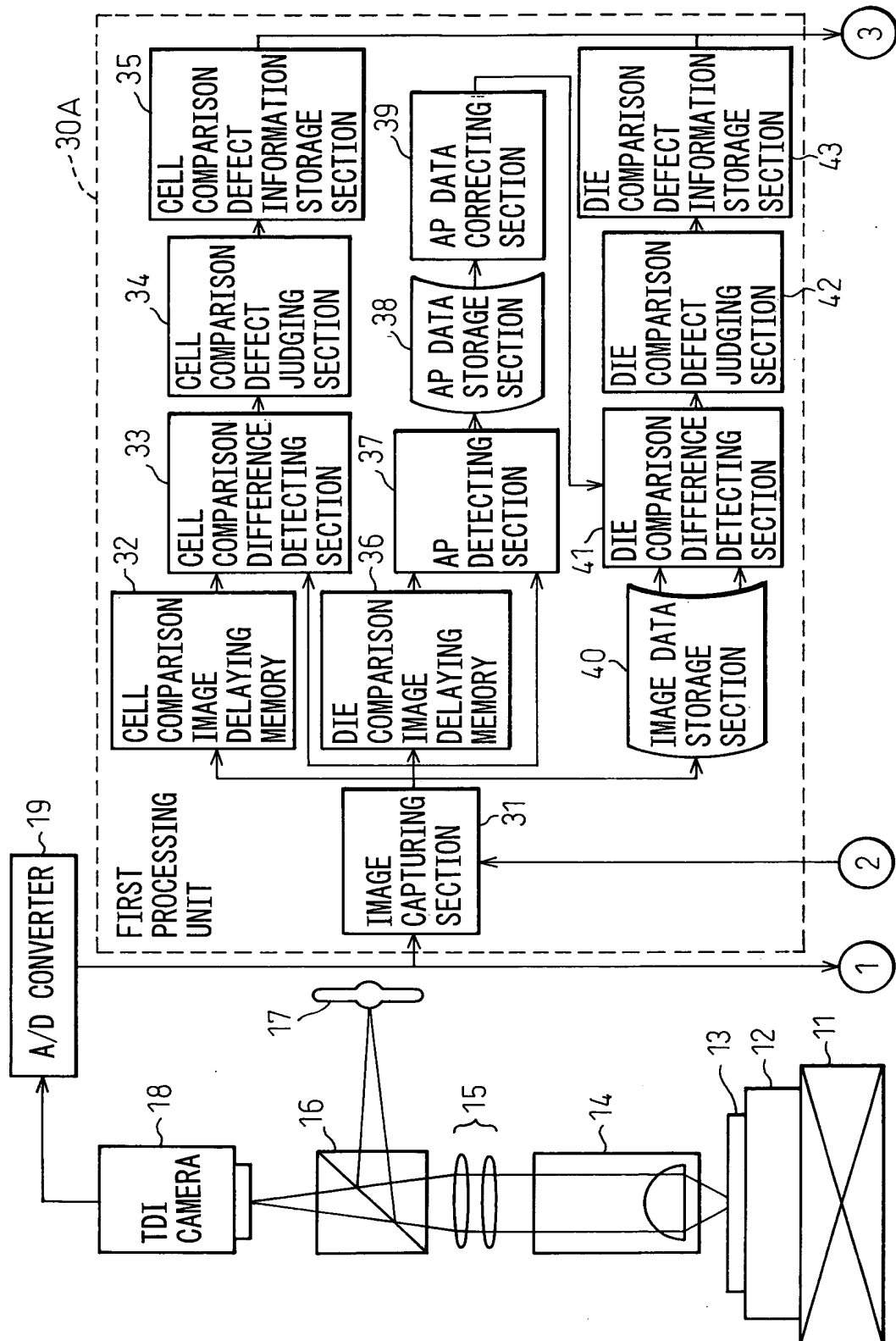
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FIG.12



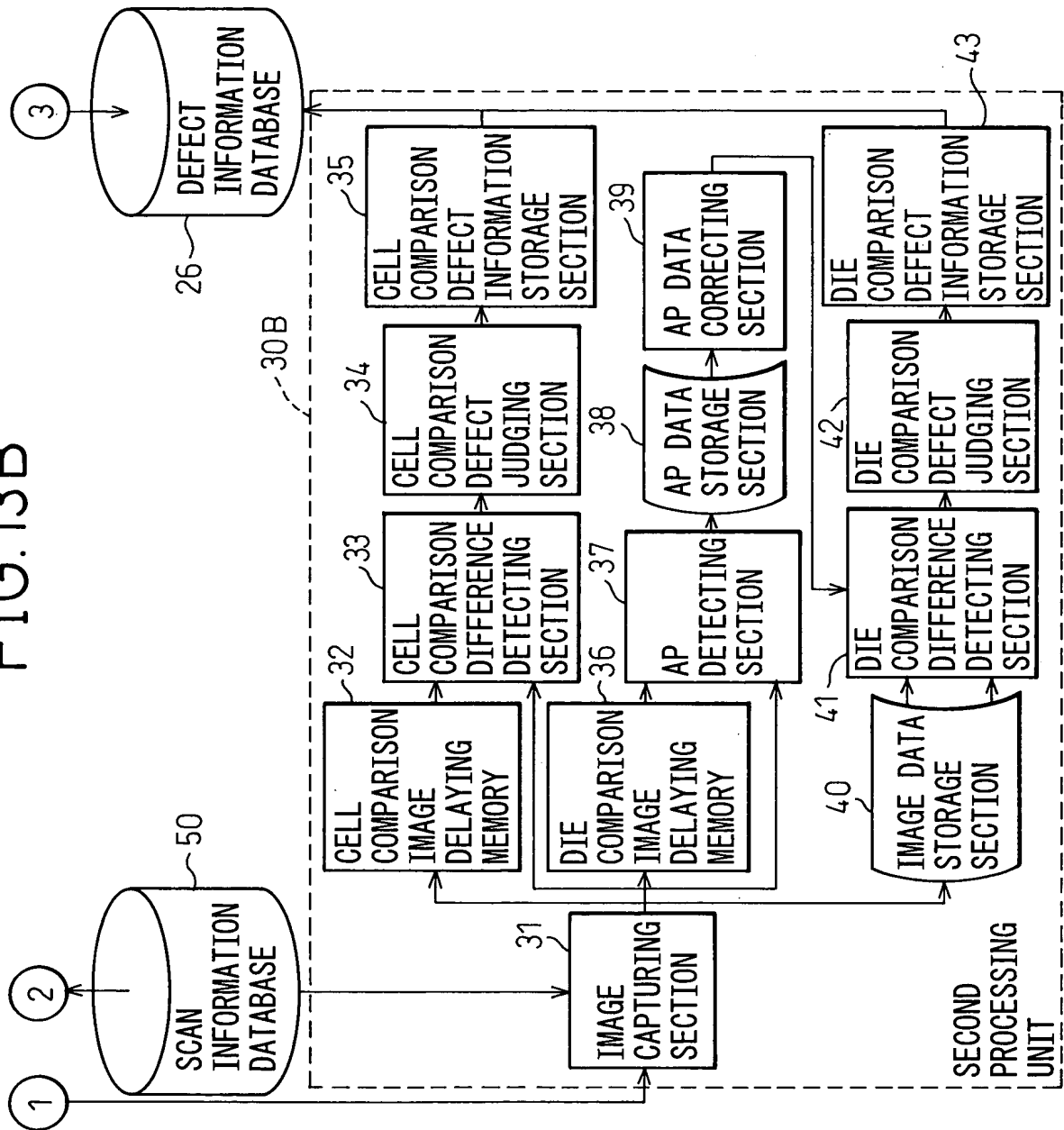
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FIG. 13A



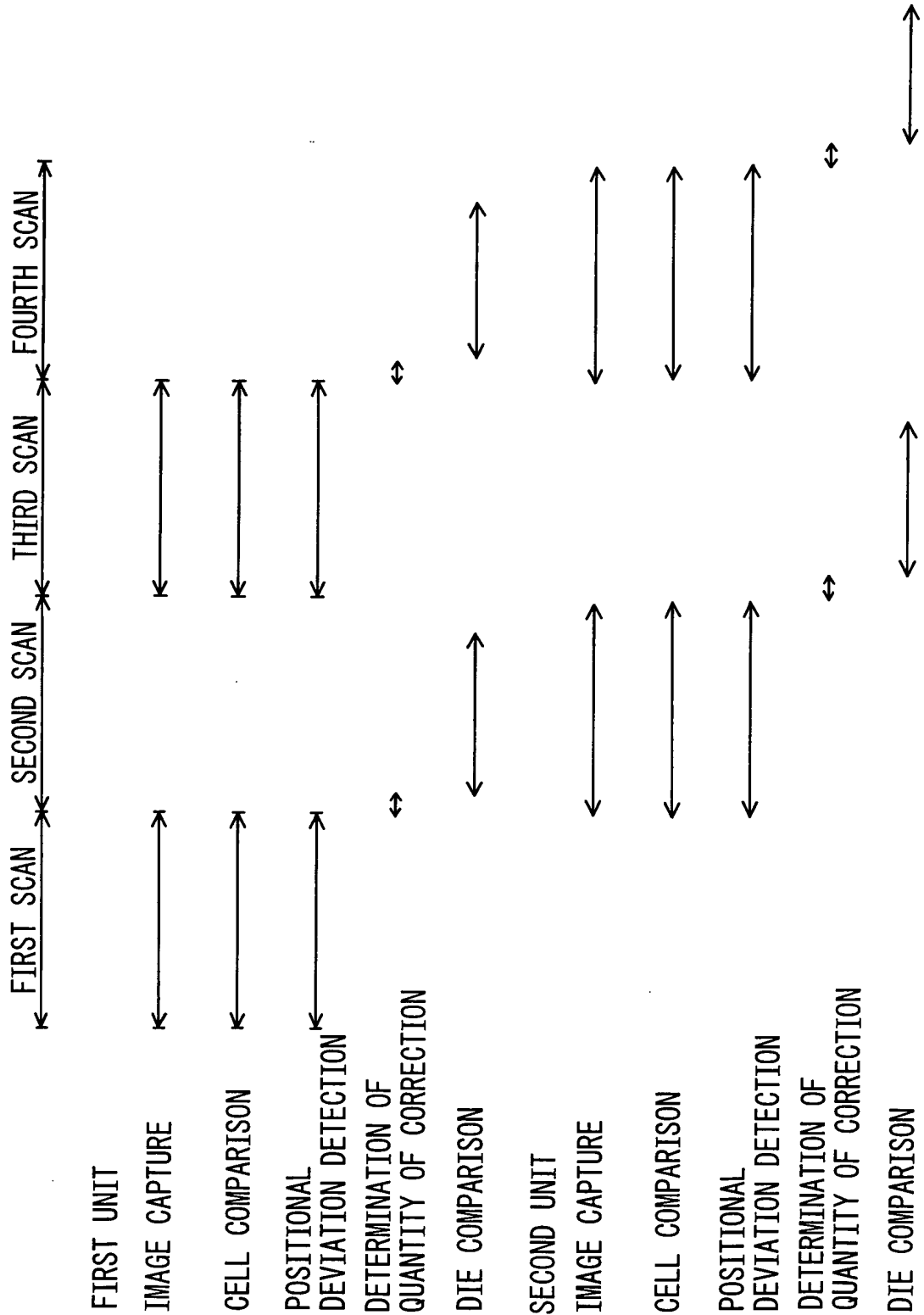
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FIG. 13B



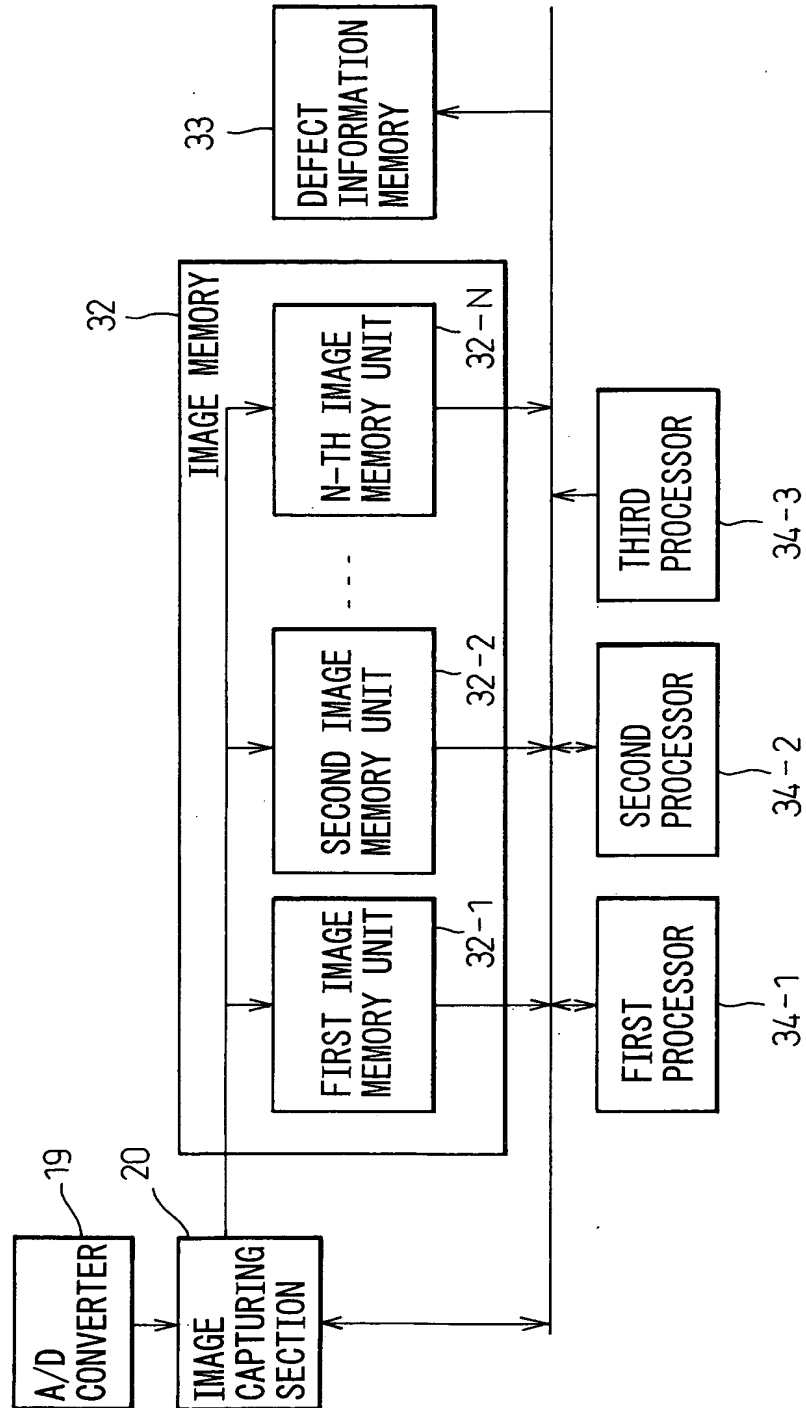
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FIG.14



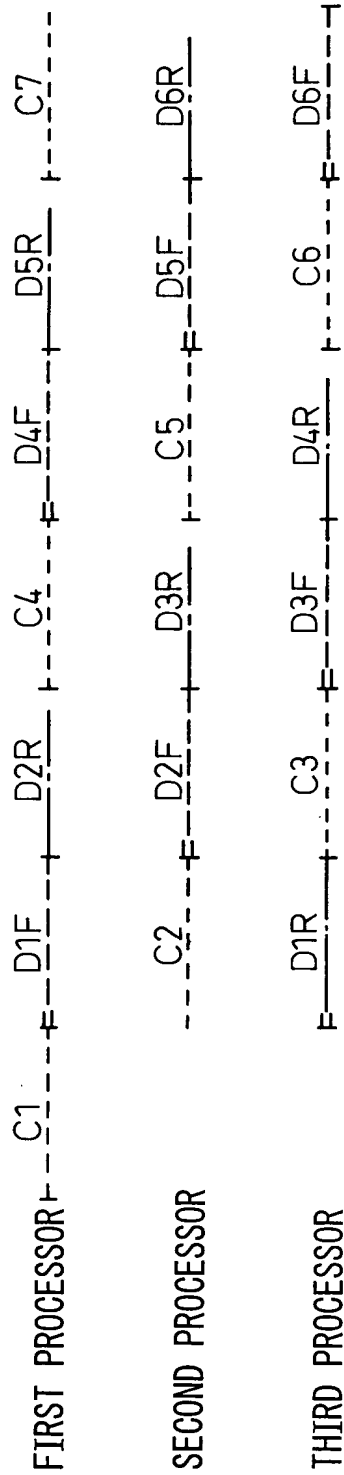
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FIG.15



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FIG.16



CN --- CELL COMPARISON AND POSITIONAL
DEVIATION DETECTION IN N-TH ROW
= DETERMINATION OF QUANTITY OF CORRECTION
DNF --- DIE COMPARISON IN FIRST HALF IN N-TH ROW
DNR --- DIE COMPARISON IN SECOND HALF IN N-TH ROW